

**Notice of References Cited**

Application/Control No.

10/729,058

Applicant(s)/Patent Under  
Reexamination  
LEE ET AL.

Examiner

ERIC YEN

Art Unit

2626

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,459,814	10-1995	Gupta et al.	704/233
*	C	US-6,708,146	03-2004	Sewall et al.	704/217
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*	E	US-6,058,359	05-2000	Hagen et al.	704/214
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*	L	US-6,978,235	12-2005	Ozawa, Kazunori	704/219
*	M	US-7,110,947	09-2006	Cox et al.	704/236

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	K	US-			
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	M	US-			

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